WEST Search History

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DATE: Thursday, October 20, 2005

Hide? Set Name Query			Hit Count	
DB=PGPB,USPT; PLUR=YES; OP=OR				
	L20	6266798[uref]	2	
	DB=US	DB=USPT,PGPB; PLUR=YES; OP=OR		
	L19	('5389874' '5594368' '5625566' '6029177')![pn]	4	
	DB=PGPB, USPT; PLUR=YES; OP=OR			
	L18	6266798[pn]	. 1	
	L17	6167554[uref]	2	
	L16	6167554[pn]	1	
	DB=USPT,PGPB; PLUR=YES; OP=OR			
	L15	('5517132' '5594368' '5818256' '5920089' '5926396')![pn]	5	
	DB=PG	PB,USPT; PLUR=YES; OP=OR		
	L14	5517132[uref]	15	
		PT,PGPB; PLUR=YES; OP=OR	•	
	L13	('4978633' '5175693' '5218551' '5404312' '5416718' '5438524')![pn]	6	
	DB=PGPB, USPT; PLUR=YES; OP=OR			
	L12	5517132[pn]	1	
	L11	"level converter?" same buffer same pair	54	
	L10	"level converter?" same buffer	444	
	L9	"level converter?" same (fanin or "fan in" or "fan-in")	. 2	
	L8	"level converter?" same cone	4.	
	L7	"minimum power point" same "level converter"	2	
	L6	"minimum power point"	45	
	L5	"level converter?" with plac\$	73	
	L4	"level converter?" with minimiz\$	20	
	L3	"level converter?" with delet\$	6	
	L2	"level converter?" with remov\$	33	
	L1	"level converter?" with eliminat\$	67	

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Search Query Display

Thu, 20 Oct 2005, 3:56:16 PM EST



Recent Search Queries

- #1 (sis<in>ti)
- #2 (sequential circuit synthesis<in>ti)
- #3 (((level converter) and placement)<in>metadata)
- #4 (((level converter) and placement)<in>metadata)
- #5 (((level converter) and (placing or place or placed or placer or places))<in>metadata)
- #6 (((level converter) and layout)<in>metadata)
- #7 (((level converter) and layout)<in>metadata)



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